

Si4466DY

Single N-Channel 2.5V Specified PowerTrench® MOSFET

General Description

This N-Channel 2.5V specified MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

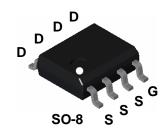
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

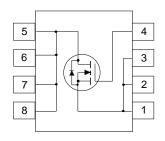
Applications

- DC/DC converter
- Load switch
- Battery protection

Features

- 15 A, 20 V. $R_{DS(on)} = 0.0075~\Omega~$ @ $V_{GS} = 4.5~V$ $R_{DS(on)} = 0.010~\Omega~$ @ $V_{GS} = 2.5~V$.
- Low gate charge (47nC typical).
- · Fast switching speed.
- \bullet High performance trench technology for extremely low $R_{\mbox{\tiny DS(ON)}}.$
- High power and current handling capability.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	15	Α
	- Pulsed		50	
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
T _J , T _{stg}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

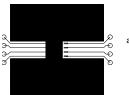
$R_{\theta^{JA}}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
$R_{\theta^{JC}}$	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

Package Outlines and Ordering Information

Device Marking	Device	Reel Size Tape Width		Quantity
4466	Si4466DY	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	•				
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C		29		mV/°C
DSS	Zero Gate Voltage Drain Current	V _{DS} = 16 V, V _{GS} = 0 V			1	μΑ
GSSF	Gate-Body Leakage, Forward	V _{GS} = 12 V, V _{DS} = 0 V			100	nA
GSSR	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	0.4	0.9	1.5	V
$\Delta V_{GS(th)} \ \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250μA, Referenced to 25°C		-4		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 4.5 V, I _D =15 A V _{GS} = 4.5 V, I _D =15 A, T _J =125°C V _{GS} = 2.5 V, I _D =12 A		0.006 0.009 0.008	0.0075 0.0130 0.0100	Ω
I _{D(on)}	On-State Drain Current	V _{GS} = 4.5 V, V _{DS} = 5.0 V	25			Α
g _{FS}	Forward Transconductance	V _{DS} = 5 V, I _D = 15 A		70		S
Dvnamio	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$		4700		pF
Coss	Output Capacitance	f = 1.0 MHz		850		pF
Crss	Reverse Transfer Capacitance			310		pF
Switchir	ng Characteristics (Note 2)		•			
d(on)	Turn-On Delay Time	$V_{DD} = 10 \text{ V}, I_D = 1 \text{ A},$		20	32	ns
r	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$		27	44	ns
d(off)	Turn-Off Delay Time	7		95	133	ns
if .	Turn-Off Fall Time			35	56	ns
Q_g	Total Gate Charge	V _{DS} = 10 V, I _D = 15 A,		47	66	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$,		7		nC
Q_{gd}	Gate-Drain Charge			10.5		nC
Drain-Sc	ource Diode Characteristics a	nd Maximum Ratings				
ls	Maximum Continuous Drain-Se				2.1	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.1 \text{ A} \text{ (Note 2)}$		0.65	1.2	V

^{1.} R_{BJA} is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta JA}$ is determined by the user's board design.







a) 50° C/W when mounted on a 0.5 in² pad of 2 oz. copper.

b) 105° C/W when mounted on a 0.02 in² pad of 2 oz. copper.

c) 125° C/W when mounted on a 0.003 in² pad of 2 oz. copper.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width $\leq 300~\mu\text{s},~\text{Duty Cycle} \leq 2.0\%$

Typical Characteristics

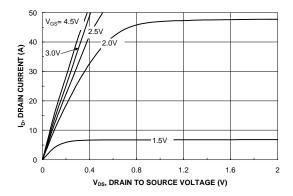


Figure 1. On-Region Characteristics.

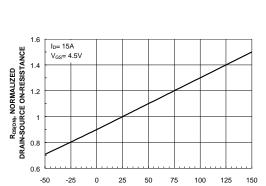


Figure 3. On-Resistance Variation with Temperature.

T_J, JUNCTION TEMPERATURE (°C)

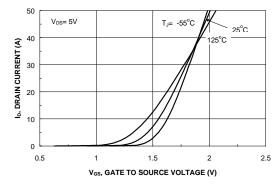


Figure 5. Transfer Characteristics.

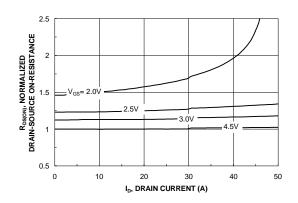


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

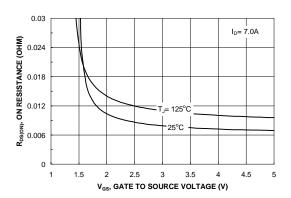


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

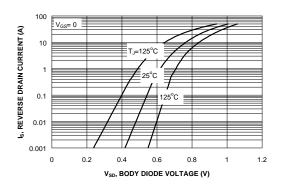
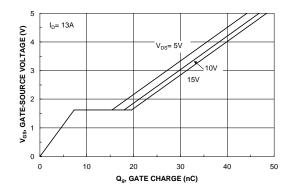


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



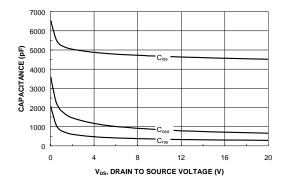
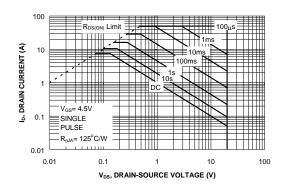


Figure 7. Gate Charge Characteristics.





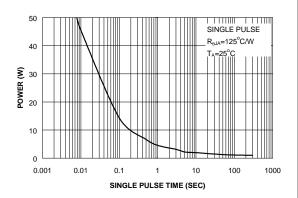


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

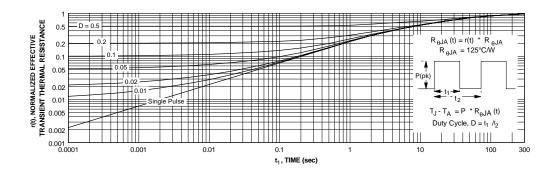


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient themal response will change depending on the circuit board design.

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